

Notice of References Cited	Application/Control No. 10/576,626		Applicant(s)/Patent Under Reexamination TAKAHASHI, EIJI	
	Examiner JAMES D. NIGH		Art Unit 3685	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,204,897 A	04-1993	Wyman, Robert M.	710/200
*	B	US-5,717,604 A	02-1998	Wiggins, Christopher	709/229
*	C	US-2002/0019814 A1	02-2002	Ganesan, Krishnamurthy	705/59
*	D	US-2002/0049635 A1	04-2002	Mai et al.	705/14
*	E	US-6,388,714 B1	05-2002	Schein et al.	348/563
*	F	US-2002/0169974 A1	11-2002	McKune, Jeffrey R.	713/200
*	G	US-2003/0028889 A1	02-2003	McCoskey et al.	725/91
*	H	US-2004/0193544 A1	09-2004	Varadarajan et al.	705/059
*	I	US-7,134,144 B2	11-2006	McKune, Jeffrey R.	726/26
*	J	US-2006/0265758 A1	11-2006	Khandelwal et al.	726/027
*	K	US-7,574,406 B2	08-2009	Varadarajan et al.	705/59
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	X					

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